

Inventor: Robert J. Hillard

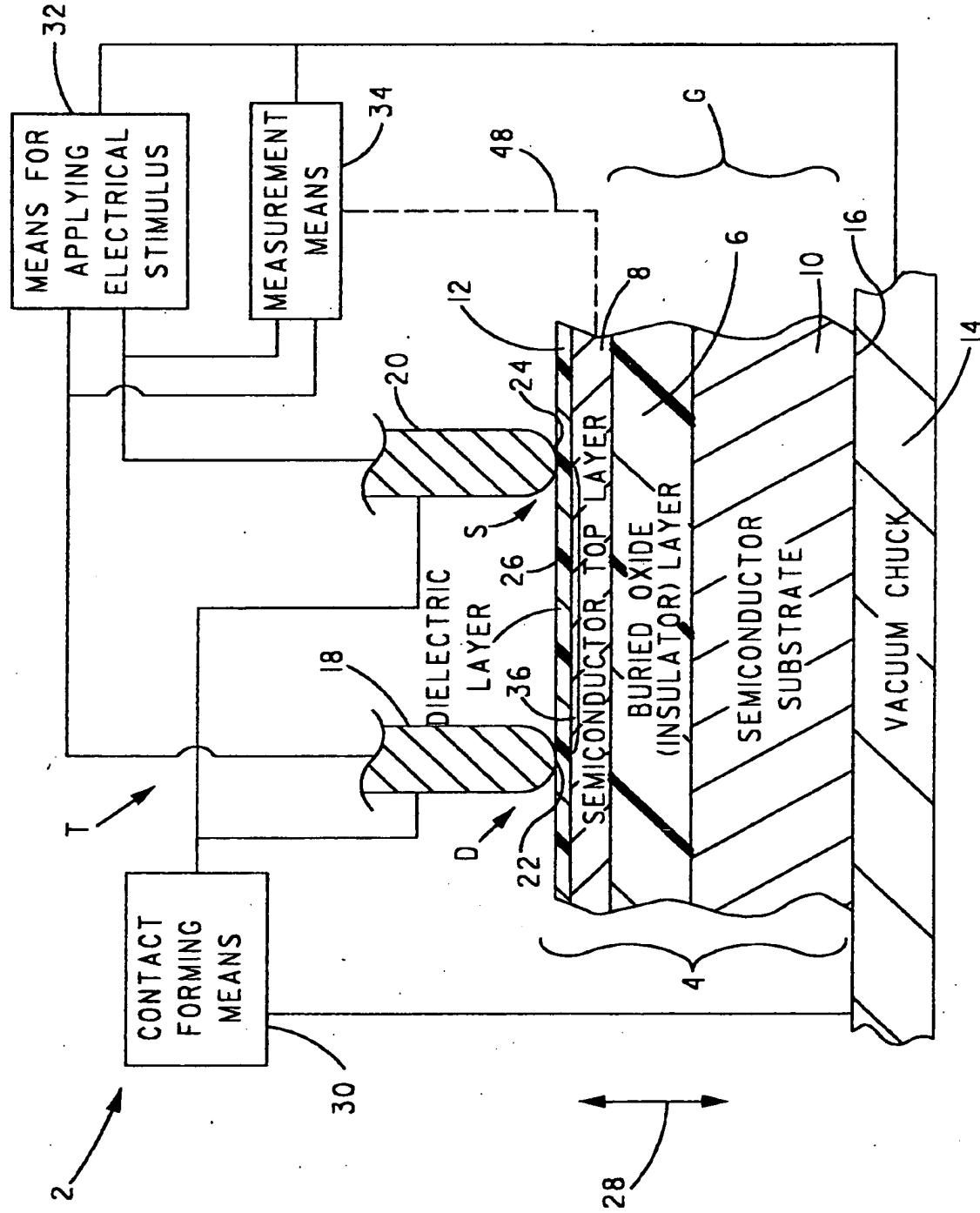
"METHOD OF ELECTRICAL CHARACTERIZATION OF A SILICON-ON-INSULATOR (SOI) WAFER"

Attorney Docket No.: 1880-031249 Application No.: 10/701,841

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FIG. 1



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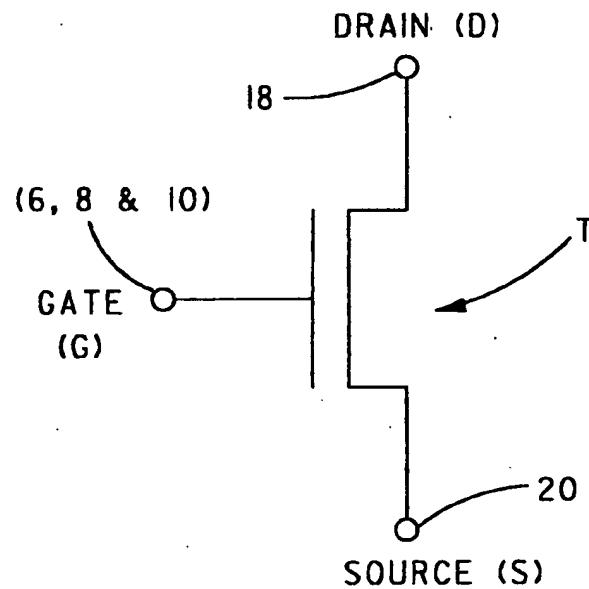


FIG. 2

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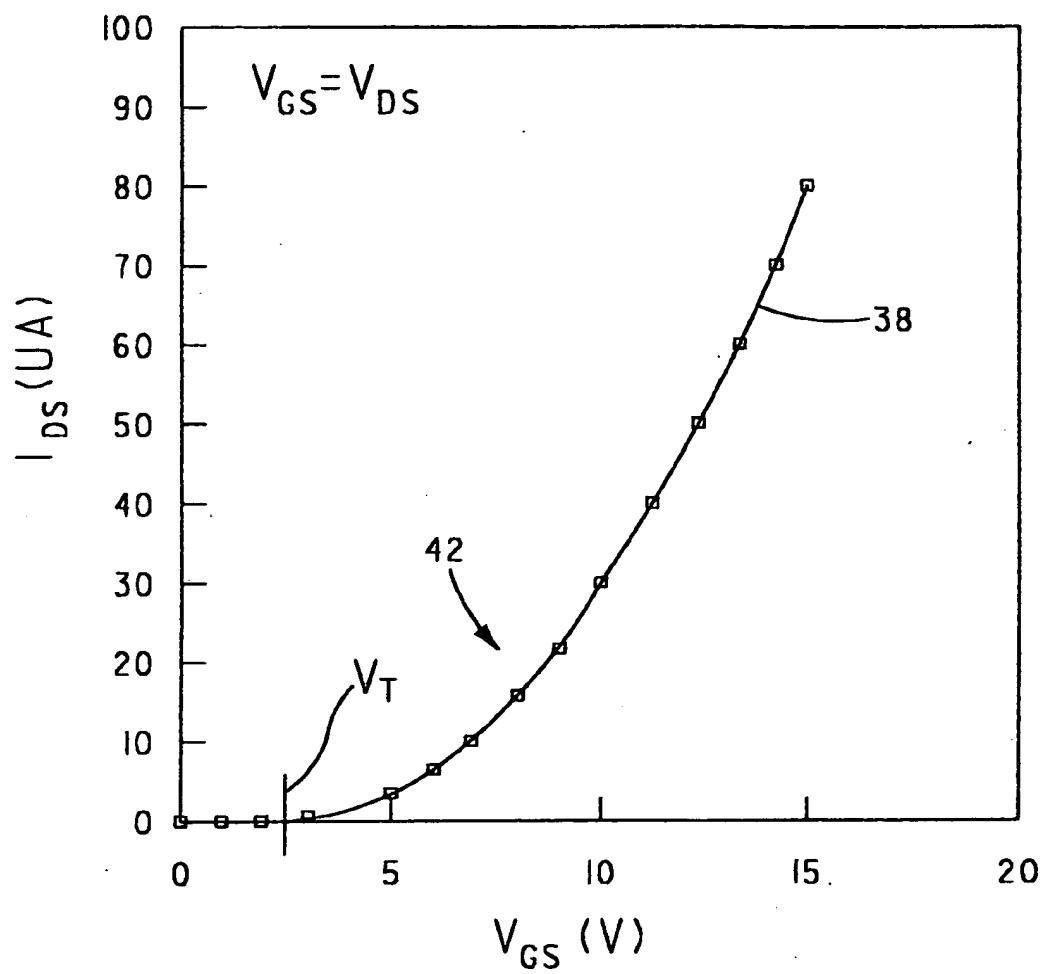


FIG. 3

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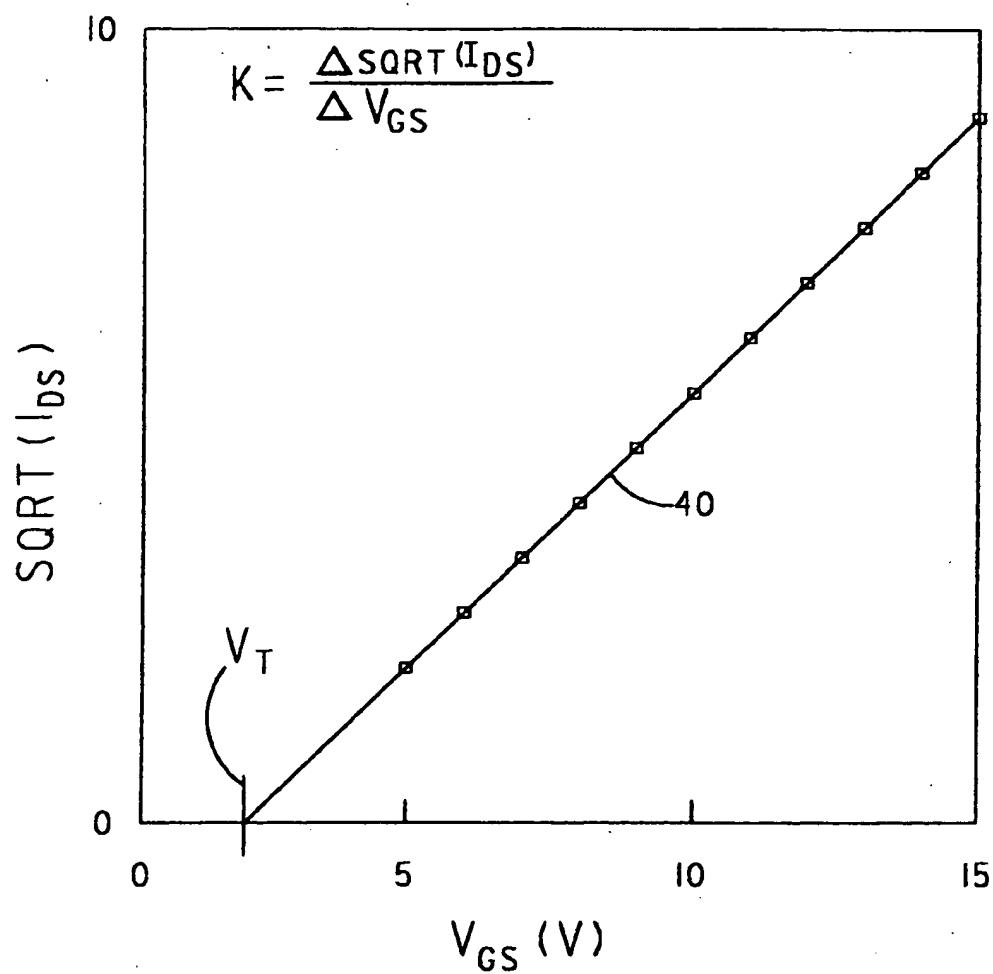


FIG. 4

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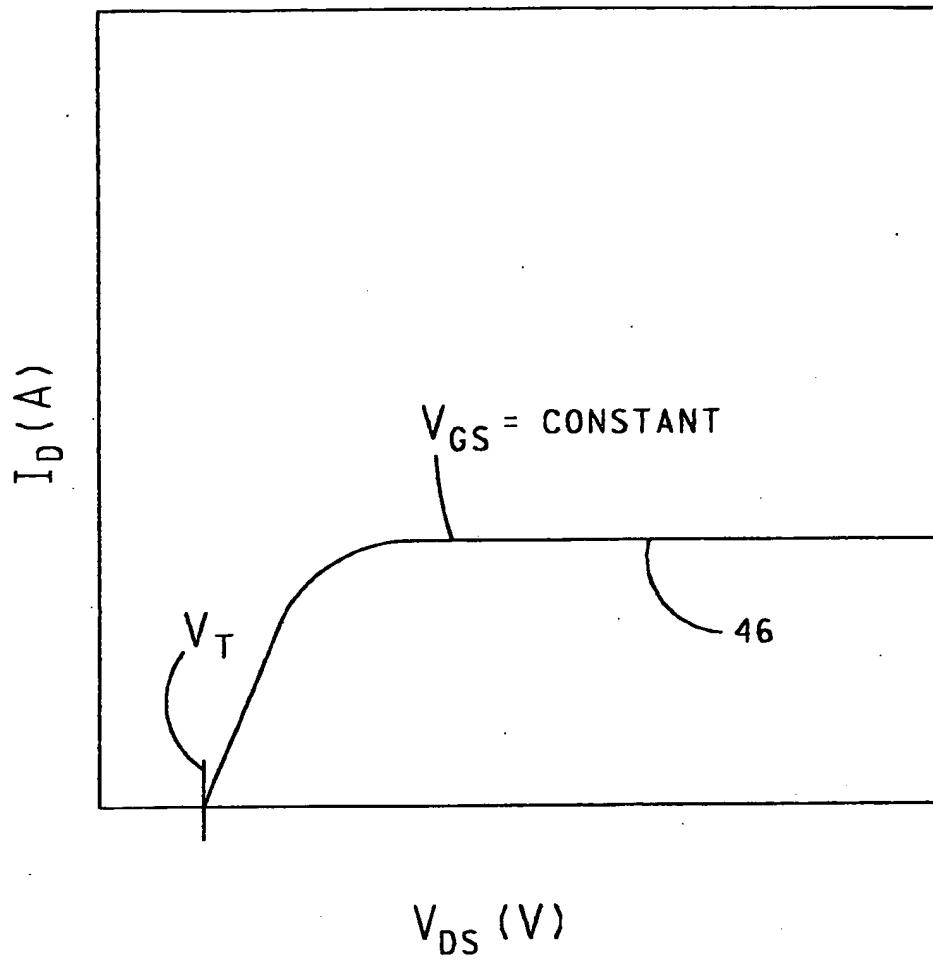


FIG. 6

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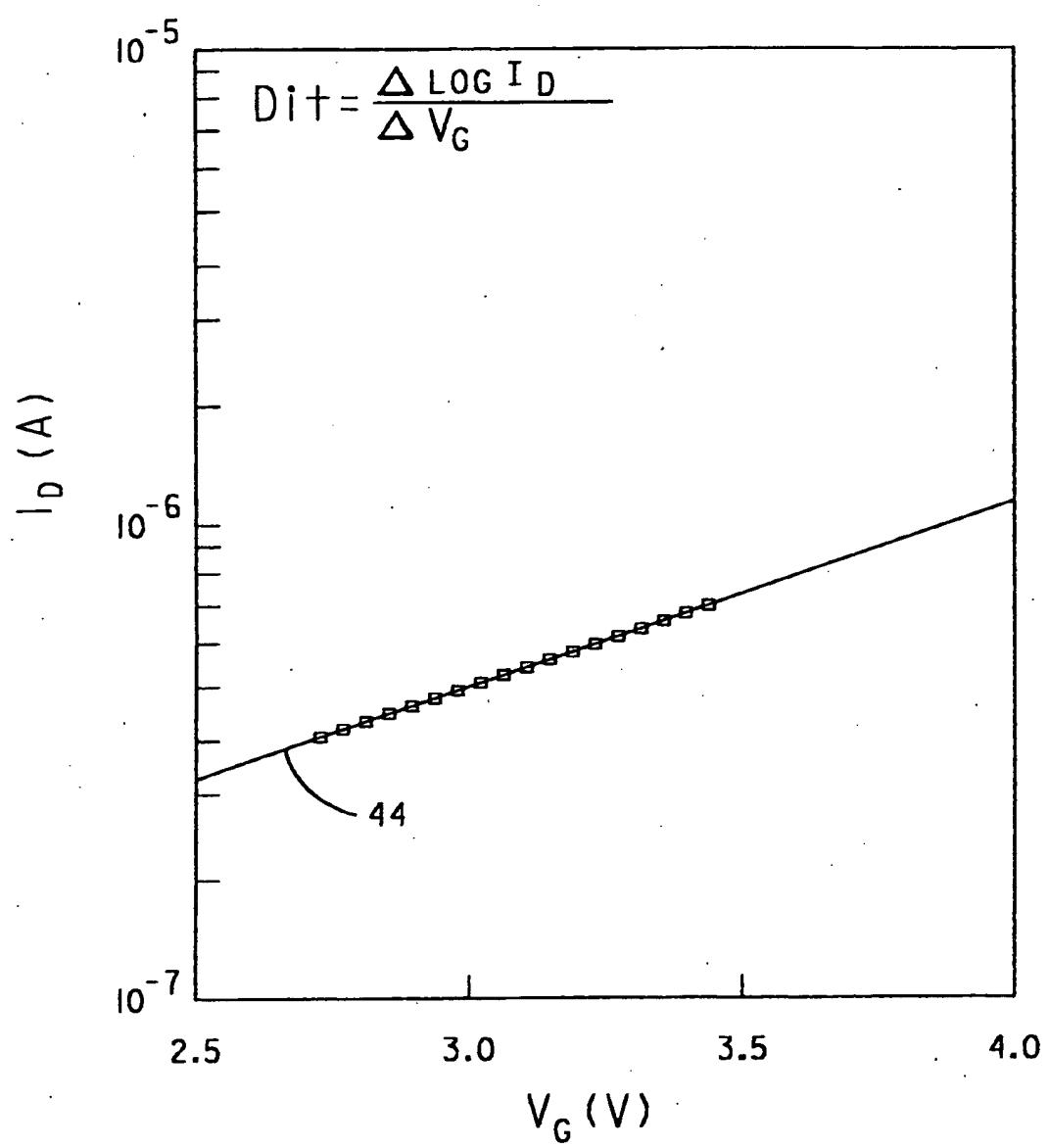


FIG. 5